

Application/Control No.	Applicant(s)/Patent under Reexamination	ier
10/798,649	LEE ET AL.	
Examiner	Art Unit	_
David J. Walczak	3751	

	SEARCHED				
Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
401	128, 132,	6/27/2006	DW		
	134, 41				
206	219				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
updated prior search	6/27/2006	DW		
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